EFM8 Sleepy Bee 1 MCU
EFM8SB1 Data Sheet

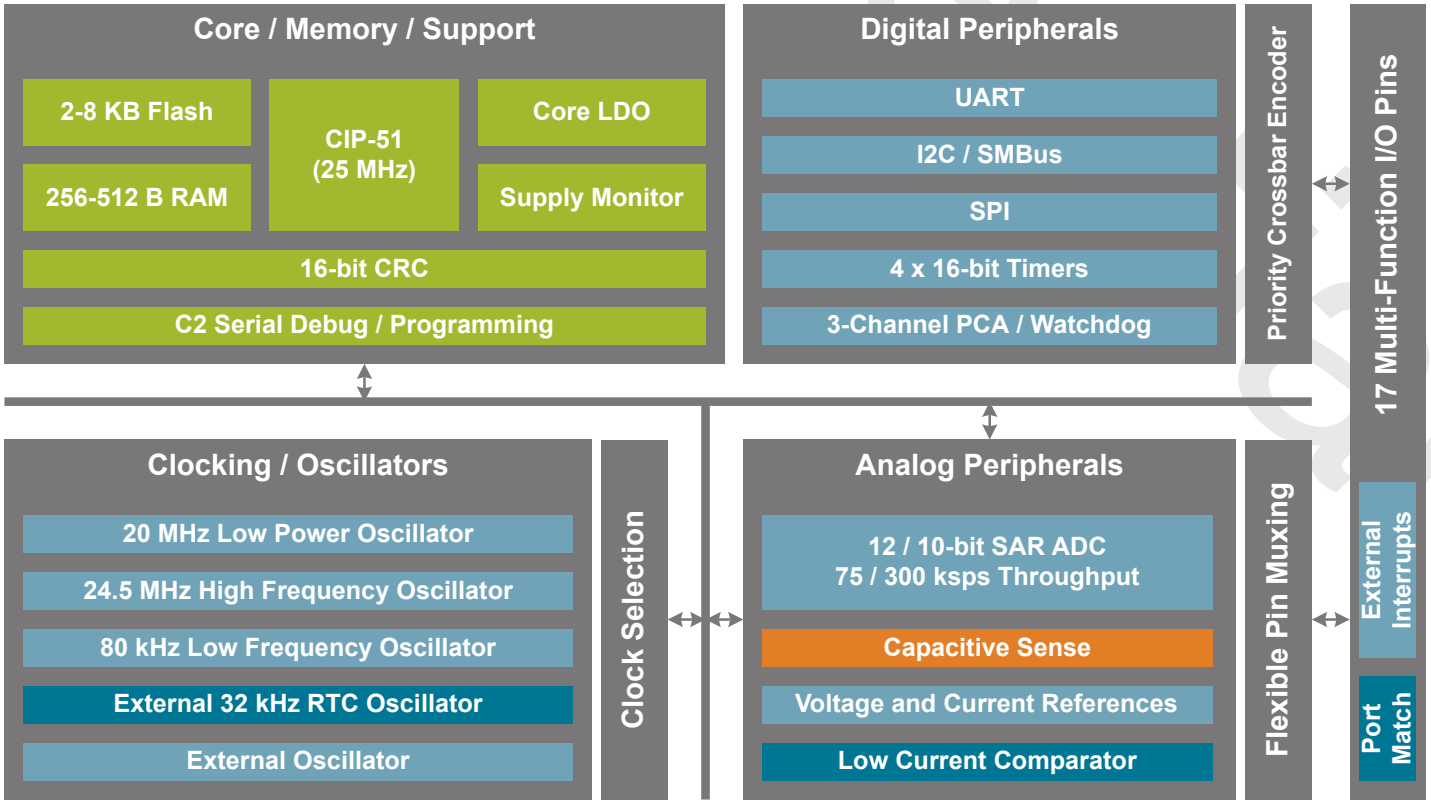
The EFM8SB1, part of the Sleepy Bee family of MCUs, is the world's most energy friendly 8 bit microcontroller. With an efficient 8 bit core, innovative low energy techniques, short wake-up times from energy saving modes, and small form factor, the EM8SB1 is well suited for any battery operated application.

In addition to 14 high quality capacitive sense channels, the EFM8SB1 has a 12-bit ADC, precision oscillator, comparator, temperature sensor, and voltage reference. The priority Crossbar enables the EFM8SB1 devices to operate in small packages by assigning only the desired peripherals to pins in a pre-defined order to eliminate pin conflicts. The EFM8SB1 creates its own class of high value and efficiency with 8, 4 or 2 kB flash sizes coupled with up to 512 RAM bytes. The EFM8SB1 is available in a 4x4 mm 24-pin QFN and 24-pin QSOP packages as well as a 3x3 mm QFN-20 package.

For more details on the peripherals available on the device, see the System Overview chapter.

ENERGY FRIENDLY FEATURES

- Lowest MCU sleep current with supply brownout (50 nA)
- Lowest MCU active current (150 µA / MHz at 24.5 MHz)
- Lowest MCU wake on touch average current (< 1 µA)
- Lowest sleep current using internal RTC and supply brownout (< 300 nA)
- Ultra-fast wake up for digital and analog peripherals (< 2 µs)
- Integrated LDO to maintain ultra-low active current at all voltages



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1. Electrical Specifications

1.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 1.1 Recommended Operating Conditions on page 1, unless stated otherwise.

Table 1.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		1.8	2.4	3.6	V
Minimum RAM Data Retention Voltage on VDD[1]	V_{RAM}	Not in Sleep Mode	—	1.4	—	V
		Sleep Mode	—	0.3	0.5	V
System Clock Frequency	f_{SYSCLK}		0	—	25	MHz
Operating Ambient Temperature	T_A		–40	—	85	°C

Note:
1. All voltages with respect to GND.

Table 1.2. Power Consumption

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Digital Supply Current						
Normal Mode supply current - Full speed with code executing from flash [3, 4, 5]	I_{DD}	V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 24.5 MHz	—	3.6	4.5	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 20 MHz	—	3.1	—	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 32.768 kHz	—	84	—	µA
Normal Mode supply current frequency sensitivity[1, 3, 5]	I_{DDFREQ}	V_{DD} = 1.8–3.6 V, T = 25 °C, f_{SYSCLK} < 14 MHz	—	174	—	µA/MHz
		V_{DD} = 1.8–3.6 V, T = 25 °C, f_{SYSCLK} > 14 MHz	—	88	—	µA/MHz
Idle Mode supply current - Core halted with peripherals running[4, 6]	I_{DD}	V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 24.5 MHz	—	1.8	3.0	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 20 MHz	—	1.4	—	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 32.768 kHz	—	82	—	µA
Idle Mode Supply Current Frequency Sensitivity[1, 6]	I_{DDFREQ}	V_{DD} = 1.8–3.6 V, T = 25 °C	—	67	—	µA/MHz
Suspend Mode Supply Current	I_{DD}	V_{DD} = 1.8–3.6 V	—	77	—	µA
Sleep Mode Supply Current with SmaRTClock running from 32.768 kHz crystal	I_{DD}	1.8 V, T = 25 °C	—	0.60	—	µA
		3.6 V, T = 25 °C	—	0.80	—	µA
		1.8 V, T = 85 °C	—	0.80	—	µA
		3.6 V, T = 85 °C	—	1.00	—	µA

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Sleep Mode Supply Current with SmaRTClock running from internal LFO	I_{DD}	1.8 V, T = 25 °C	—	0.30	—	µA
		3.6 V, T = 25 °C	—	0.50	—	µA
		1.8 V, T = 85 °C	—	0.50	—	µA
		3.6 V, T = 85 °C	—	0.80	—	µA
Sleep Mode Supply Current (SmaRTClock off)	I_{DD}	1.8 V, T = 25 °C	—	0.05	—	µA
		3.6 V, T = 25 °C	—	0.08	—	µA
		1.8 V, T = 85 °C	—	0.20	—	µA
		3.6 V, T = 85 °C	—	0.28	—	µA
Sleep Mode Supply Current (SmaRTClock and POR monitor off)	I_{DD}	1.8 V, T = 25 °C	—	0.005	—	µA
		3.6 V, T = 25 °C	—	0.02	—	µA
		1.8 V, T = 85 °C	—	0.15	—	µA
		3.6 V, T = 85 °C	—	0.23	—	µA
V_{DD} Monitor Supply Current	I_{VMON}		—	7	—	µA
Oscillator Supply Current	I_{HFOSC0}	25 °C	—	300	—	µA
ADC0 Always-on Power Supply Current[7]	I_{ADC}	300 ksps, 10-bit conversions or 75 ksps, 12-bit conversions Normal bias settings V_{DD} = 3.0 V	—	740	—	µA
		150 ksps, 10-bit conversions or 37.5 ksps 12-bit conversions Low power bias settings V_{DD} = 3.0 V	—	400	—	µA
Comparator 0 (CMP0) Supply Current	I_{CMP}	CPMD = 11	—	0.4	—	µA
		CPMD = 10	—	2.6	—	µA
		CPMD = 01	—	8.8	—	µA
		CPMD = 00	—	23	—	µA
Internal Fast-Settling 1.65V ADC0 Reference, Always-on[8]	I_{VREFFS}	Normal Power Mode	—	260	—	µA
		Low Power Mode	—	140	—	µA
Temp sensor Supply Current	I_{TSENSE}		—	35	—	µA
Capacitive Sense Module (CS0) Supply Current	I_{CS0}	CS module bias current, 25 °C	—	50	60	µA
		CS module alone, maximum code output, 25 °C	—	90	125	µA
		Wake-on-CS threshold (suspend mode with regulator and CS module on)[9]	—	130	180	µA

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Programmable Current Reference (IREF0) Supply Current[10]	I_{IREF0}	Current Source, Either Power Mode, Any Output Code	—	10	—	µA
		Low Power Mode, Current Sink IREF0DAT = 000001	—	1	—	µA
		Low Power Mode, Current Sink IREF0DAT = 111111	—	11	—	µA
		High Current Mode, Current Sink IREF0DAT = 000001	—	12	—	µA
		High Current Mode, Current Sink IREF0DAT = 111111	—	81	—	µA

Note:

1. Based on device characterization data; Not production tested.
2. SYSCLK must be at least 32 kHz to enable debugging.
3. Digital Supply Current depends upon the particular code being executed. The values in this table are obtained with the CPU executing an "sjmp $" loop, which is the compiled form of a while(1) loop in C. One iteration requires 3 CPU clock cycles, and the flash memory is read on each cycle. The supply current will vary slightly based on the physical location of the sjmp instruction and the number of flash address lines that toggle as a result. In the worst case, current can increase by up to 30% if the sjmp loop straddles a 64-byte flash address boundary (e.g., 0x007F to 0x0080). Real-world code with larger loops and longer linear sequences will have few transitions across the 64-byte address boundaries.
4. Includes supply current from regulator and oscillator source (24.5 MHz high-frequency oscillator, 20 MHz low-power oscillator, 1 MHz external oscillator, or 32.768 kHz SmaRTClock oscillator).
5. IDD can be estimated for frequencies < 14 MHz by simply multiplying the frequency of interest by the frequency sensitivity number for that range, then adding an offset of 84 µA. When using these numbers to estimate I_{DD} for > 14 MHz, the estimate should be the current at 25 MHz minus the difference in current indicated by the frequency sensitivity number. For example: V_{DD} = 3.0 V; F = 20 MHz, I_{DD} = 3.6 mA – (25 MHz – 20 MHz) x 0.088 mA/MHz = 3.16 mA assuming the same oscillator setting.
6. Idle IDD can be estimated by taking the current at 25 MHz minus the difference in current indicated by the frequency sensitivity number. For example: V_{DD} = 3.0 V; F = 5 MHz, Idle I_{DD} = 1.75 mA – (25 MHz – 5 MHz) x 0.067 mA/MHz = 0.41 mA.
7. ADC0 always-on power excludes internal reference supply current.
8. The internal reference is enabled as-needed when operating the ADC in burst mode to save power.
9. Includes only current from regulator, CS module, and MCU in suspend mode.
10. IREF0 supply current only. Does not include current sourced or sunk from IREF0 output pin.

Table 1.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}	Reset Trigger	1.7	1.75	1.8	V
	V_{WARN}	Early Warning	1.8	1.85	1.9	V
VDD Supply Monitor Turn-On Time	t_{MON}		—	300	—	ns
Power-On Reset (POR) Monitor Threshold	V_{POR}	Rising Voltage on V_{DD}	—	1.75	—	V
		Falling Voltage on V_{DD}	0.45	0.7	1.0	V
V_{DD} Ramp Time	t_{RMP}	Time to $V_{DD} \geq$ 1.8 V	—	—	3	ms
Reset Delay	t_{RST}	Time between release of reset source and code execution	—	10	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	F_{SYSCLK} > 1 MHz	100	650	1000	µs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7	10	kHz

Table 1.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1]	t_{WRITE}	One Byte	57	64	71	µs
Erase Time[1]	t_{ERASE}	One Page	28	32	36	ms
Endurance (Write/Erase Cycles)	N_{WE}		20 k	100 k	—	Cycles

Note:
1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. Data Retention Information is published in the Quarterly Quality and Reliability Report.

Table 1.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUSPENDWK}$	CLKDIV = 0x00 Low Power or Precision Osc.	—	400	—	ns
Sleep Mode Wake-up Time	$t_{SLEEPWK}$		—	2	—	µs

Table 1.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Low Power Oscillator (20 MHz)						
Oscillator Frequency	f_{LPOSC}	Full Temperature and Supply Range	18	20	22	MHz
Low Frequency Oscillator (16.4 kHz internal RTC oscillator)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	13.1	16.4	19.7	kHz

Table 1.7. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	-	25	MHz

Table 1.8. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	25	MHz

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock High Time	t_{CMOSH}		18	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		18	—	—	ns

Table 1.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate	f_S	12 Bit Mode	—	—	75	ksps
		10 Bit Mode	—	—	300	ksps
Tracking Time	t_{TRK}	Initial Acquisition	1.5	—	—	us
		Subsequent Acquisitions (DC input, burst mode)	1.1	—	—	us
Power-On Time	t_{PWR}		1.5	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode,	—	—	8.33	MHz
		Low Power Mode	—	—	4.4	MHz
Conversion Time	T_{CNV}	10-Bit Conversion	13	—	—	Clocks
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	16	—	pF
		Gain = 0.5	—	13	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	5	—	kΩ
Voltage Reference Range	V_{REF}		1	—	V_{DD}	V
Input Voltage Range[1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	2 x V_{REF}	V
Power Supply Rejection Ratio	$PSRR_{ADC}$	Internal High Speed VREF	—	67	—	dB
		External VREF	—	74	—	dB
DC Performance						
Integral Nonlinearity	INL	12 Bit Mode	—	±1	±1.5	LSB
		10 Bit Mode	—	±0.5	±1	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode	—	±0.8	±1	LSB
		10 Bit Mode	—	±0.5	±1	LSB
Offset Error	E_{OFF}	12 Bit Mode, VREF = 1.65 V	–2.5	0	2.5	LSB
		10 Bit Mode, VREF = 1.65 V	–2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C
Slope Error	E_M	12 Bit Mode	—	±0.02	±0.1	%
		10 Bit Mode	—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput						

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Signal-to-Noise	SNR	12 Bit Mode	62	65	—	dB
		10 Bit Mode	54	58	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	62	65	—	dB
		10 Bit Mode	54	58	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	-76	—	dB
		10 Bit Mode	—	-73	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	82	—	dB
		10 Bit Mode	—	75	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.
2. INL and DNL specifications for 12-bit mode do not include the first or last four ADC codes.
3. The maximum code in 12-bit mode is 0xFFFC. The Full Scale Error is referenced from the maximum code.

Table 1.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage	V_{REFFS}		1.62	1.65	1.68	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
External Reference						
Input Voltage	V_{EXTREF}		1	—	V_{DD}	V
Input Current	I_{EXTREF}	Sample Rate = 300 ksps; VREF = 3.0 V	—	5.25	—	µA

Table 1.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	T_A = 0 °C	—	940	—	mV
Offset Error[1]	E_{OFF}	T_A = 0 °C	—	18	—	mV
Slope	M		—	3.40	—	mV/°C
Slope Error[1]	E_M		—	40	—	µV/°C
Linearity			—	±1	—	°C
Turn-on Time	t_{PWR}		—	1.8	—	µs

Note:
1. Represents one standard deviation from the mean.

Table 1.12. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	120	—	ns
		–100 mV Differential	—	110	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential	—	1.25	—	µs
		–100 mV Differential	—	3.2	—	µs
Positive Hysterisis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysterisis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	–8	—	mV
		CPHYN = 10	—	–16	—	mV
		CPHYN = 11	—	–32	—	mV
Positive Hysterisis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysterisis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	–6	—	mV
		CPHYN = 10	—	–12	—	mV
		CPHYN = 11	—	–24	—	mV
Positive Hysterisis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysterisis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	–4.5	—	mV
		CPHYN = 10	—	–9	—	mV
		CPHYN = 11	—	–18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	–4	—	mV
		CPHYN = 10	—	–8	—	mV
		CPHYN = 11	—	–16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Range (CP+ or CP–)	V_{IN}		-0.25	—	V_{DD}+0.25	V
Input Pin Capacitance	C_{CP}		—	12	—	pF
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°C

Table 1.13. Programmable Current Reference (IREF0)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Performance						
Resolution	N_{bits}			6		bits
Output Compliance Range	V_{IOUT}	Low Power Mode, Source	0	—	V_{DD} – 0.4	V
		High Current Mode, Source	0	—	V_{DD} – 0.8	V
		Low Power Mode, Sink	0.3	—	V_{DD}	V
		High Current Mode, Sink	0.8	—	V_{DD}	V
Integral Nonlinearity	INL		—	<±0.2	±1.0	LSB
Differential Nonlinearity	DNL		—	<±0.2	±1.0	LSB
Offset Error	E_{OFF}		—	<±0.1	±0.5	LSB
Full Scale Error	E_{FS}	Low Power Mode, Source	—	—	±5	%
		High Current Mode, Source	—	—	±6	%
		Low Power Mode, Sink	—	—	±8	%
		High Current Mode, Sink	—	—	±8	%
Absolute Current Error	E_{ABS}	Low Power Mode Sourcing 20 µA	—	<±1	±3	%
Dynamic Performance						
Output Settling Time to 1/2 LSB	t_{SETTLE}		—	300	—	ns
Startup Time	t_{PWR}		—	1	—	µs

Note:
1. The PCA block may be used to improve IREF0 resolution by PWMing the two LSBs.

Table 1.14. Capacitive Sense (CS0)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Single Conversion Time[1]	t_{CNV}	12-bit Mode	20	25	40	µs
		13-bit Mode (default)	21	27	42.5	µs
		14-bit Mode	23	29	45	µs
		16-bit Mode	26	33	50	µs

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Number of Channels	N_{CHAN}	24-pin Packages		17		Channels
		20-pin Packages		16		Channels
Capacitance per Code	C_{LSB}	Default Configuration, 16-bit codes	—	1	—	fF
Maximum External Capacitive Load	C_{EXTMAX}	CS0CG = 111b (Default)	—	45	—	pF
		CS0CG = 000b	—	500	—	pF
Maximum External Series Impedance	R_{EXTMAX}	CS0CG = 111b (Default)	—	50	—	kΩ

Note:
1. Conversion time is specified with the default configuration.
2. RMS Noise is equivalent to one standard deviation. Peak-to-peak noise encompasses ±3.3 standard deviations. The RMS noise value is specified with the default configuration.

Table 1.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	I_{OH} = –3 mA	V_{DD} – 0.7	—	—	V
Output Low Voltage (High Drive)	V_{OL}	I_{OL} = 8.5 mA	—	—	0.6	V
Output High Voltage (Low Drive)	V_{OH}	I_{OH} = –1 mA	V_{DD} – 0.7	—	—	V
Output Low Voltage (Low Drive)	V_{OL}	I_{OL} = 1.4 mA	—	—	0.6	V
Input High Voltage	V_{IH}	V_{DD} = 2.0 to 3.6 V	V_{DD} – 0.6	—	—	V
		V_{DD} = 1.8 to 2.0 V	0.7 x V_{DD}	—	—	V
Input Low Voltage	V_{IL}	V_{DD} = 2.0 to 3.6 V	—	—	0.6	V
		V_{DD} = 1.8 to 2.0 V	—	—	0.3 x V_{DD}	V
Weak Pull-Up Current	I_{PU}	V_{DD} = 1.8 V V_{IN} = 0 V	—	–4	—	µA
		V_{DD} = 3.6 V V_{IN} = 0 V	–35	–20	—	µA
Input Leakage	I_{LK}	Weak pullup disabled or pin in analog mode	–1	—	1	µA

1.2 Thermal Conditions

Table 1.16. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance*	JA	QFN-24 Packages	—	35	—	°C/W
		QFN-20 Packages	—	60	—	°C/W
		QSOP-24 Packages	—	65	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

1.3 Absolute Maximum Ratings

Stresses above those listed in Table 1.17 Absolute Maximum Ratings on page 10 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 1.17. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on V_{DD}	V_{DD}		GND–0.3	4.0	V
Voltage on I/O pins or RSTb	V_{IN}		GND–0.3	V_{DD} + 0.3	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I_{IO}		-100	100	mA
Maximum Total Current through all Port Pins	I_{IOTOT}		—	200	mA
Operating Junction Temperature	T_J		–40	105	°C
Exposure to maximum rating conditions for extended periods may affect device reliability.					

1.4 Typical Performance Curves

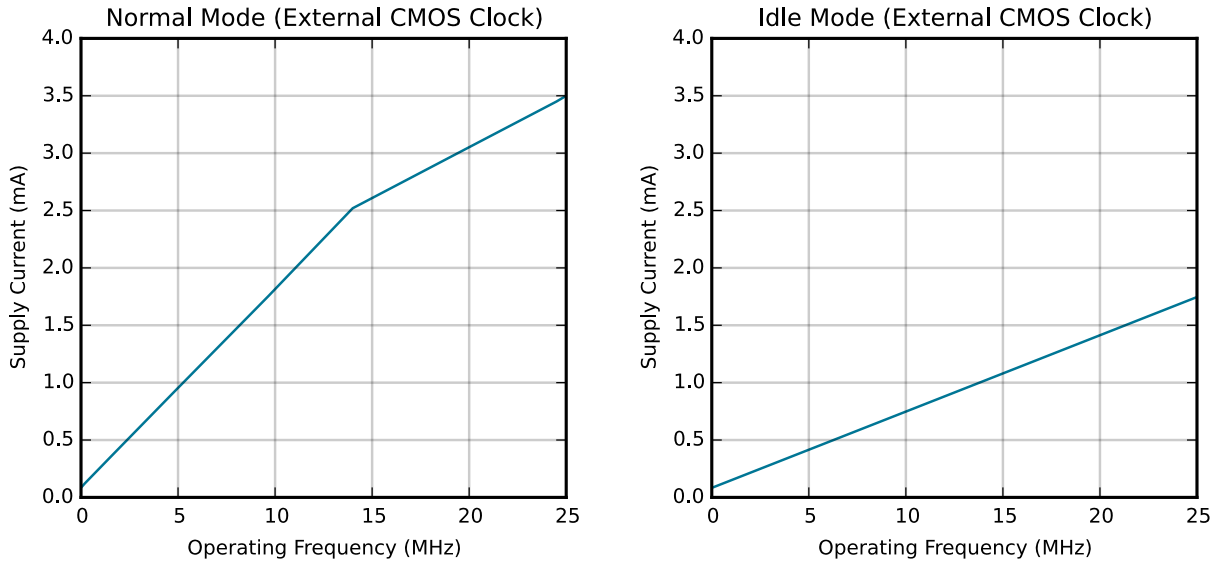

Figure 1.1. Typical Operating Supply Current (full supply voltage range)

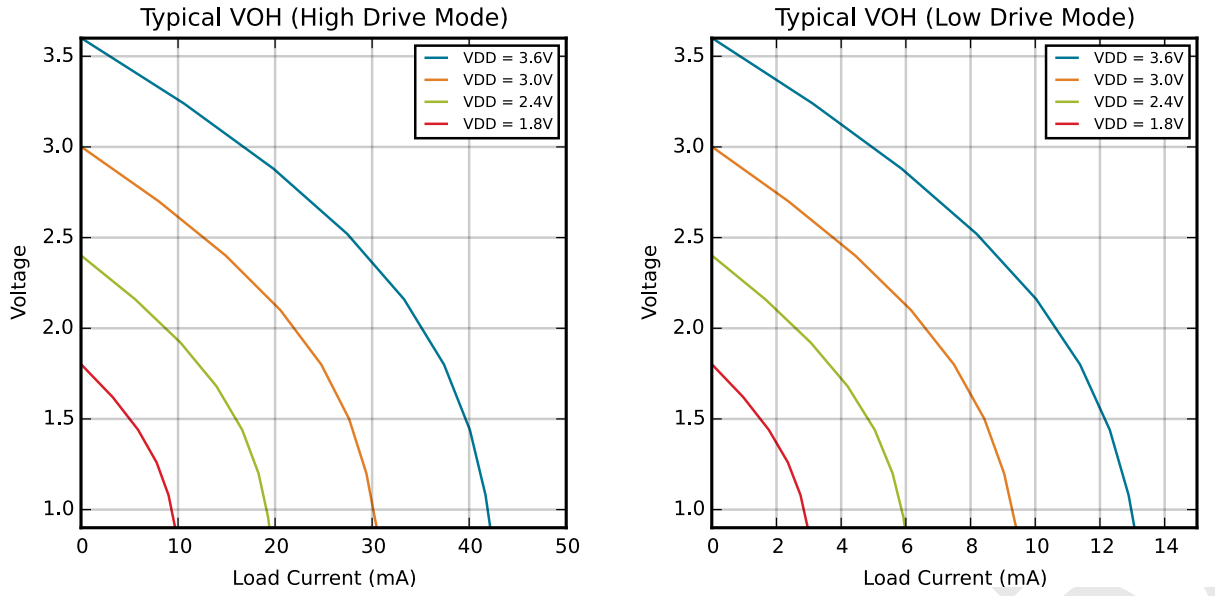

Figure 1.2. Typical V_{OH} Curves

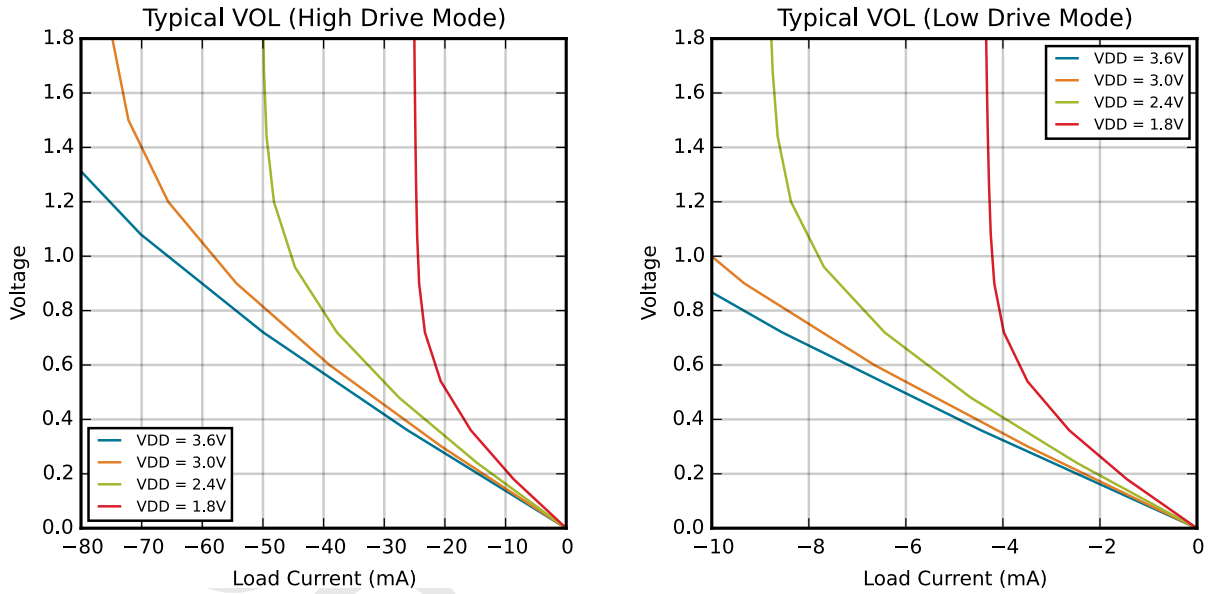

Figure 1.3. Typical V_{OL} Curves

2. System Overview

2.1 Introduction

The EFM8SB1 device family are fully integrated, mixed-signal system-on-a-chip MCUs. Highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 25 MHz maximum operating frequency
- Memory:
  - Up to 8 kB flash memory, in-system re-programmable from firmware.
  - Up to 512 bytes RAM (including 256 bytes standard 8051 RAM and 256 bytes on-chip XRAM)
- Power:
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 17 total multifunction I/O pins:
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 20 MHz low power oscillator with ±10% accuracy
  - Internal 24.5 MHz precision oscillator with ±2% accuracy
  - Internal 16.4 kHz low-frequency oscillator or RTC 32 kHz crystal
  - External crystal, RC, C, and CMOS clock options
- Timers/Counters and PWM:
  - 32-bit Real Time Clock (RTC)
  - 3-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes with watchdog timer function
  - 4 x 16-bit general-purpose timers
- Communications and Digital Peripherals:
  - UART
  - SPI™ Master / Slave
  - SMBus™ / I2C™ Master / Slave
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
- Analog:
  - Capacitive Sense (CS0)
  - Programmable current reference (IREF0)
  - 12-Bit Analog-to-Digital Converter (ADC0)
  - 1 x Low-current analog comparator
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8SB1 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing non-volatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 1.8 to 3.6 V operation and is available in 20-pin QFN, 24-pin QFN, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

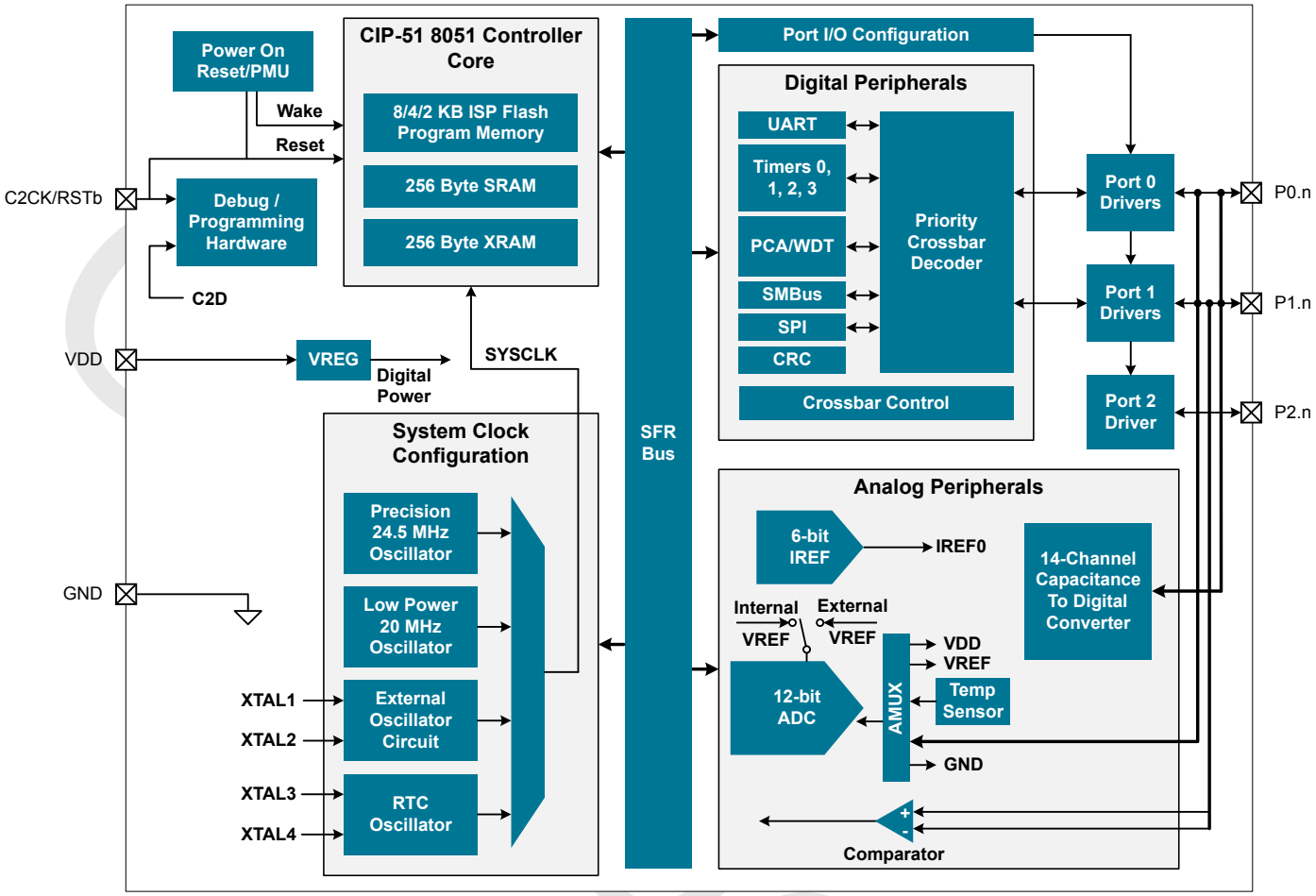

Figure 2.1. Detailed EFM8SB1 Block Diagram

2.2 Power

All internal circuitry draws power from the VDD supply pin. Circuits with external connections (I/O pins, analog muxes) are powered directly from the VDD supply voltage, while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 2.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	—	—
Idle	• Core halted • All peripherals clocked and fully operational • Code resumes execution on wake event	Set IDLE bit in PCON0	Any interrupt
Suspend	• Core and digital peripherals halted • Internal oscillators disabled • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 or LPOSC0 2. Set SUSPEND bit in PMU0CF	• RTC0 Alarm Event • RTC0 Fail Event • CS0 Interrupt • Port Match Event • Comparator 0 Rising Edge
Sleep	• Most internal power nets shut down • Select circuits remain powered • Pins retain state • All RAM and SFRs retain state • Code resumes execution on wake event	1. Disable unused analog peripherals 2. Set SLEEP bit in PMU0CF	• RTC0 Alarm Event • RTC0 Fail Event • Port Match Event • Comparator 0 Rising Edge

2.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P1.7 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pin P2.7 can be used as GPIO. P2.7 is shared with the C2 Interface Data signal (C2D).

- Up to 17 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- Up to 16 direct-pin interrupt sources with shared interrupt vector (Port Match).

2.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 20 MHz low power oscillator divided by 8.

- Provides clock to core and peripherals.
- 20 MHz low power oscillator (LPOSC0), accurate to ±10% over supply and temperature corners.
- 24.5 MHz internal oscillator (HFOSC0), accurate to ±2% over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0) or external RTC 32 kHz crystal.
- External RC, C, CMOS, and high-frequency crystal clock options (EXTCLK).
- Clock divider with eight settings for flexible clock scaling: Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.

2.5 Counters/Timers and PWM

Real Time Clock (RTC0)

The RTC is an ultra low power, 36 hour 32-bit independent time-keeping Real Time Clock with alarm. The RTC has a dedicated 32 kHz oscillator that can be configured for use with or without a crystal. No external resistor or loading capacitors are required, and a missing clock detector features alerts the system if the external crystal fails. The on-chip loading capacitors are programmable to 16 discrete levels allowing compatibility with a wide range of crystals.

The RTC module includes the following features:

- Up to 36 hours (32-bit) of independent time keeping.
- Support for internal 16.4 kHz low frequency oscillator (LFOSC) or external 32 kHz crystal.
- Internal crystal loading capacitors with 16 levels.
- Operation in the lowest power mode and across the full supported voltage range.
- Alarm and oscillator failure events to wake from the lowest power mode or reset the device.
- Buffered clock output available for other system devices even in the lowest power mode.

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base
- Programmable clock divisor and clock source selection
- Three independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (edge-aligned operation)
- Frequency output mode
- Capture on rising, falling or any edge
- Compare function for arbitrary waveform generation
- Software timer (internal compare) mode
- Integrated watchdog timer

Timers (Timer 0, Timer 1, Timer 2, and Timer 3)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0).

Timer 2 and Timer 3 are 16-bit timers including the following features:

- Clock sources include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8.
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- Comparator 0 or RTC0 capture (Timer 2)
- RTC0 or EXTCLK/8 capture (Timer 3)

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) integrated within the PCA0 peripheral. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software. The state of the RSTb pin is unaffected by this reset.

The Watchdog Timer integrated in the PCA0 peripheral has the following features:

- Programmable timeout interval
- Runs from the selected PCA clock source
- Automatically enabled after any system reset

2.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions
- Baud rates up to SYSCLK / 2 (transmit) or SYSCLK / 8 (receive)
- 8- or 9-bit data
- Automatic start and stop generation

Serial Peripheral Interface (SPI0)

The serial peripheral interface (SPI) module provides access to a flexible, full-duplex synchronous serial bus. The SPI can operate as a master or slave device in both 3-wire or 4-wire modes, and supports multiple masters and slaves on a single SPI bus. The slave-select (NSS) signal can be configured as an input to select the SPI in slave mode, or to disable master mode operation in a multi-master environment, avoiding contention on the SPI bus when more than one master attempts simultaneous data transfers. NSS can also be configured as a firmware-controlled chip-select output in master mode, or disabled to reduce the number of pins required. Additional general purpose port I/O pins can be used to select multiple slave devices in master mode.

The SPI module includes the following features:

- Supports 3- or 4-wire operation in master or slave modes.
- Supports external clock frequencies up to SYSCLK / 2 in master mode and SYSCLK / 10 in slave mode.
- Support for four clock phase and polarity options.
- 8-bit dedicated clock clock rate generator.
- Support for multiple masters on the same data lines.

System Management Bus / I2C (SMBus0)

The SMBus I/O interface is a two-wire, bi-directional serial bus. The SMBus is compliant with the System Management Bus Specification, version 1.1, and compatible with the I^2C serial bus.

The SMBus module includes the following features:

- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds.
- Support for master, slave, and multi-master modes.
- Hardware synchronization and arbitration for multi-master mode.
- Clock low extending (clock stretching) to interface with faster masters.
- Hardware support for 7-bit slave and general call address recognition.
- Firmware support for 10-bit slave address decoding.
- Ability to inhibit all slave states.
- Programmable data setup/hold times.

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial.
- Byte-level bit reversal.
- Automatic CRC of flash contents on one or more 256-byte blocks.
- Initial seed selection of 0x0000 or 0xFFFF.

2.7 Analog

Capacitive Sense (CS0)

The Capacitive Sense subsystem uses a capacitance-to-digital circuit to determine the capacitance on a port pin. The module can take measurements from different port pins using the module's analog multiplexer. The module can be configured to take measurements on one port pin, a group of port pins one-by-one using auto-scan, or the total capacitance on multiple channels together. A selectable gain circuit allows the designer to adjust the maximum allowable capacitance. An accumulator is also included, which can be configured to average multiple conversions on an input channel. Interrupts can be generated when the CS0 peripheral completes a conversion or when the measured value crosses a configurable threshold.

The Capacitive Sense module includes the following features:

- Measure multiple pins one-by-one using auto-scan or total capacitance on multiple channels together.
- Configurable input gain.
- Hardware auto-accumulate and average.
- Multiple internal start-of-conversion sources.
- Operational in Suspend when all other clocks are disabled.
- Interrupts available at the end of a conversion or when the measured value crosses a configurable threshold.

Programmable Current Reference (IREF0)

The programmable current reference (IREF0) module enables current source or sink with two output current settings: Low Power Mode and High Current Mode. The maximum current output in Low Power Mode is 63 µA (1 µA steps) and the maximum current output in High Current Mode is 504 µA (8 µA steps).

The IREF module includes the following features:

- Capable of sourcing or sinking current in programmable steps.
- Two operational modes: Low Power Mode and High Current Mode.
- Fine-tuning mode for higher output precision available in conjunction with the PCA0 module.

12-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12-, 10-, and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 10 external inputs.
- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 75 ksps samples per second in 12-bit mode or 300 ksps samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal 1.65 V fast-settling reference and support for external reference.
- Integrated temperature sensor.

Low Current Comparator (CMP0)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator module includes the following features:

- Up to 1 external positive input.
- Up to 1 external negative input.
- Additional input options:
  - Capacitive Sense Comparator output.
  - VDD.
  - VDD divided by 2.
  - Internal connection to LDO output.
  - Direct connection to GND.
- Synchronous and asynchronous outputs can be routed to pins via crossbar.
- Programmable hysteresis between 0 and +/-20 mV.
- Programmable response time.
- Interrupts generated on rising, falling, or both edges.

2.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For VDD Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset
- RTC0 alarm or oscillator failure

2.9 Debugging

The EFM8SB1 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

3. Ordering Information

All EFM8SB1 family members have the following features:

- CIP-51 Core running up to 25 MHz
- Three Internal Oscillators (24.5 MHz, 20 MHz, and 16 kHz)
- SMBus / I2C
- SPI
- UART
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 4 16-bit Timers
- Analog Comparator
- 6-bit current sourc reference
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit

In addition to these features, each part number in the EFM8SB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 3.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Capacitive Touch Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8SB10F8G-A-QSOP24	8	512	17	10	14	Yes	-40 to +85 C	QSOP24
EFM8SB10F8G-A-QFN24	8	512	17	10	14	Yes	-40 to +85 C	QFN24
EFM8SB10F8G-A-QFN20	8	512	16	9	13	Yes	-40 to +85 C	QFN20
EFM8SB10F4G-A-QFN20	4	512	16	9	13	Yes	-40 to +85 C	QFN20
EFM8SB10F2G-A-QFN20	2	256	16	9	13	Yes	-40 to +85 C	QFN20

4. Pin Definitions

4.1 EFM8SB1x-QFN20 Pin Definitions

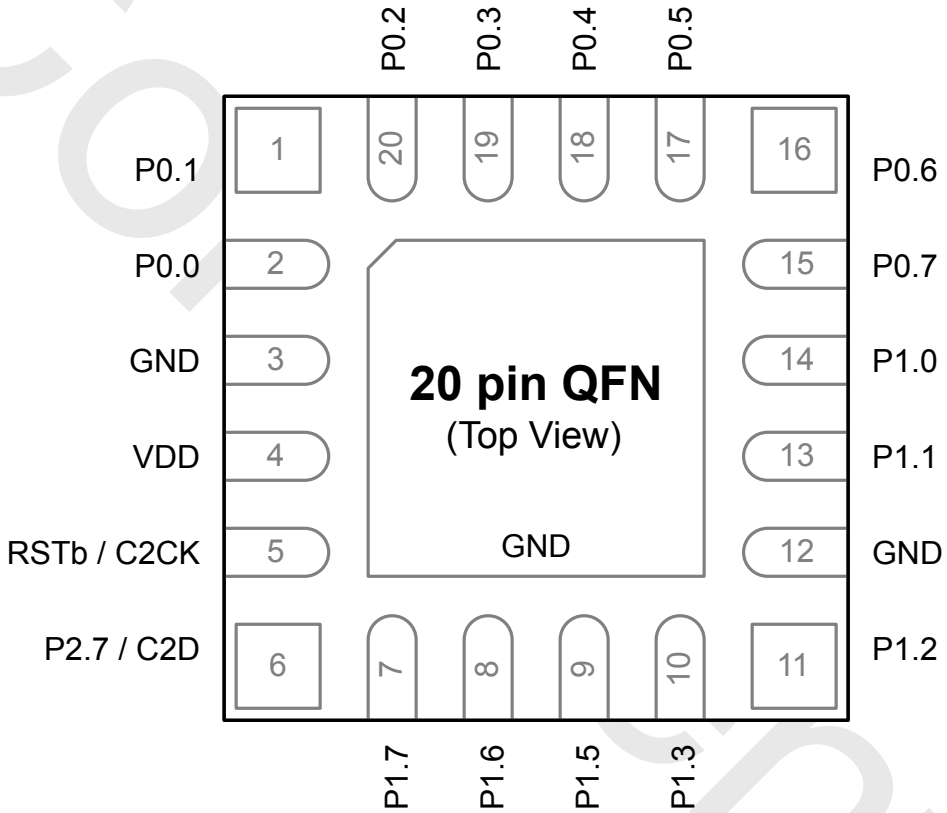

Figure 4.1. EFM8SB1x-QFN20 Pinout

Table 4.1. Pin Definitions for EFM8SB1x-QFN20

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CS0.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	CS0.0 VREF
3	GND	Ground			
4	VDD	Supply Power Input			

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P2.7 / C2D	Multifunction I/O / C2 Debug Data			
7	P1.7	Multifunction I/O	Yes	P1MAT.7	XTAL4
8	P1.6	Multifunction I/O	Yes	P1MAT.6	XTAL3
9	P1.5	Multifunction I/O	Yes	P1MAT.5	CS0.13
10	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CS0.11
11	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CS0.10
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	CMP0N.4 CS0.9
14	P1.0	Multifunction I/O	Yes	P1MAT.0	CMP0P.4 CS0.8
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CS0.7 IREF0
16	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CS0.6
17	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CS0.5
18	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CS0.4
19	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK WAKEOUT INT0.3 INT1.3	ADC0.3 CS0.3 XTAL2
20	P0.2	Multifunction I/O	Yes	P0MAT.2 RTCOUT INT0.2 INT1.2	ADC0.2 CS0.2 XTAL1
Center	GND	Ground			

4.2 EFM8SB1x-QFN24 Pin Definitions

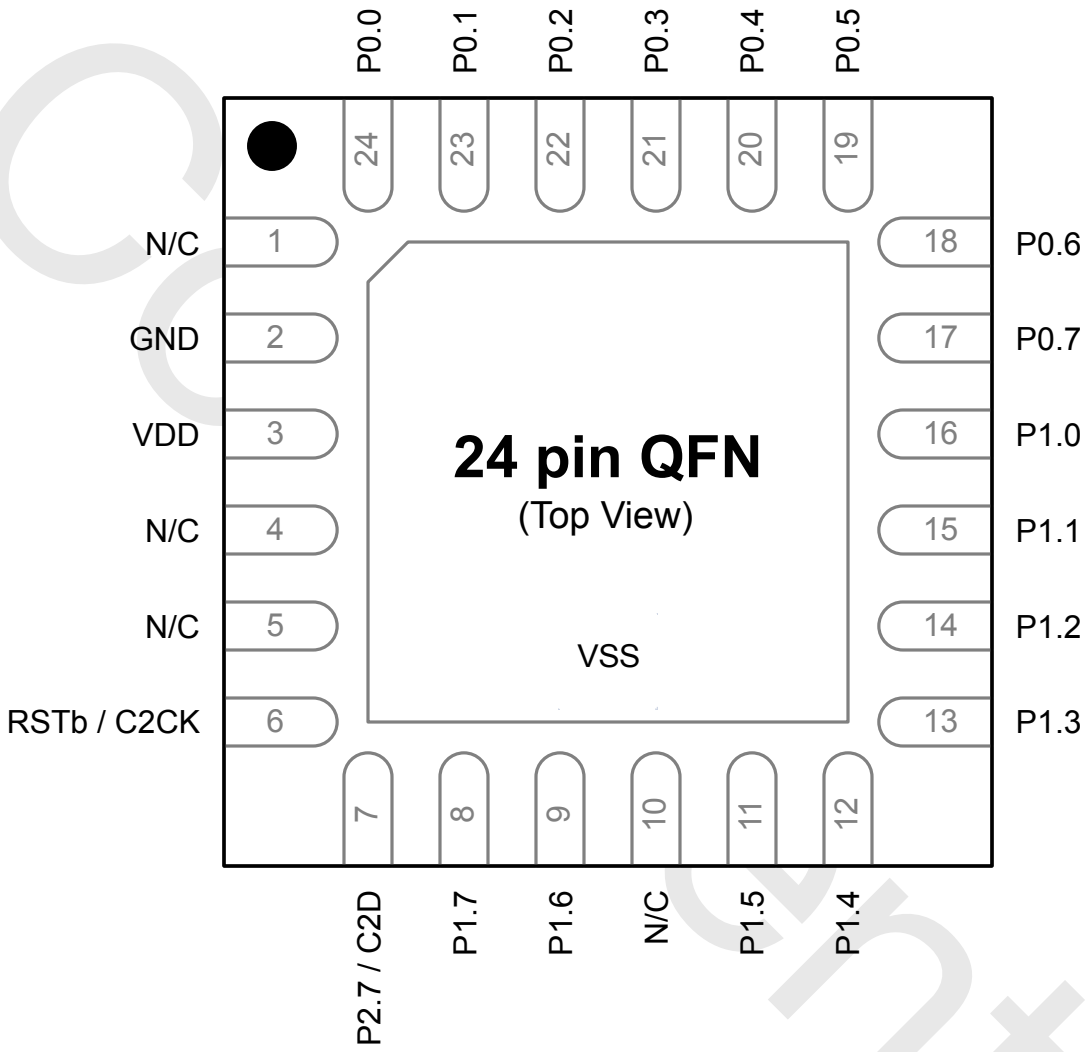

Figure 4.2. EFM8SB1x-QFN24 Pinout

Table 4.2. Pin Definitions for EFM8SB1x-QFN24

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			
5	N/C	No Connection			

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
6	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
7	P2.7 / C2D	Multifunction I/O / C2 Debug Data			
8	P1.7	Multifunction I/O	Yes	P1MAT.7	XTAL4
9	P1.6	Multifunction I/O	Yes	P1MAT.6	XTAL3
10	N/C	No Connection			
11	P1.5	Multifunction I/O	Yes	P1MAT.5	CS0.13
12	P1.4	Multifunction I/O	Yes	P1MAT.4	CS0.12
13	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CS0.11
14	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CS0.10
15	P1.1	Multifunction I/O	Yes	P1MAT.1	CMP0N.4 CS0.9
16	P1.0	Multifunction I/O	Yes	P1MAT.0	CMP0P.4 CS0.8
17	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CS0.7 IREF0
18	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CS0.6
19	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CS0.5
20	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CS0.4
21	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK WAKEOUT INT0.3 INT1.3	ADC0.3 CS0.3 XTAL2
22	P0.2	Multifunction I/O	Yes	P0MAT.2 RTCOUT INT0.2 INT1.2	ADC0.2 CS0.2 XTAL1
23	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CS0.1 AGND

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
24	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	CS0.0 VREF
Center	GND	Ground			

4.3 EFM8SB1x-QSOP24 Pin Definitions

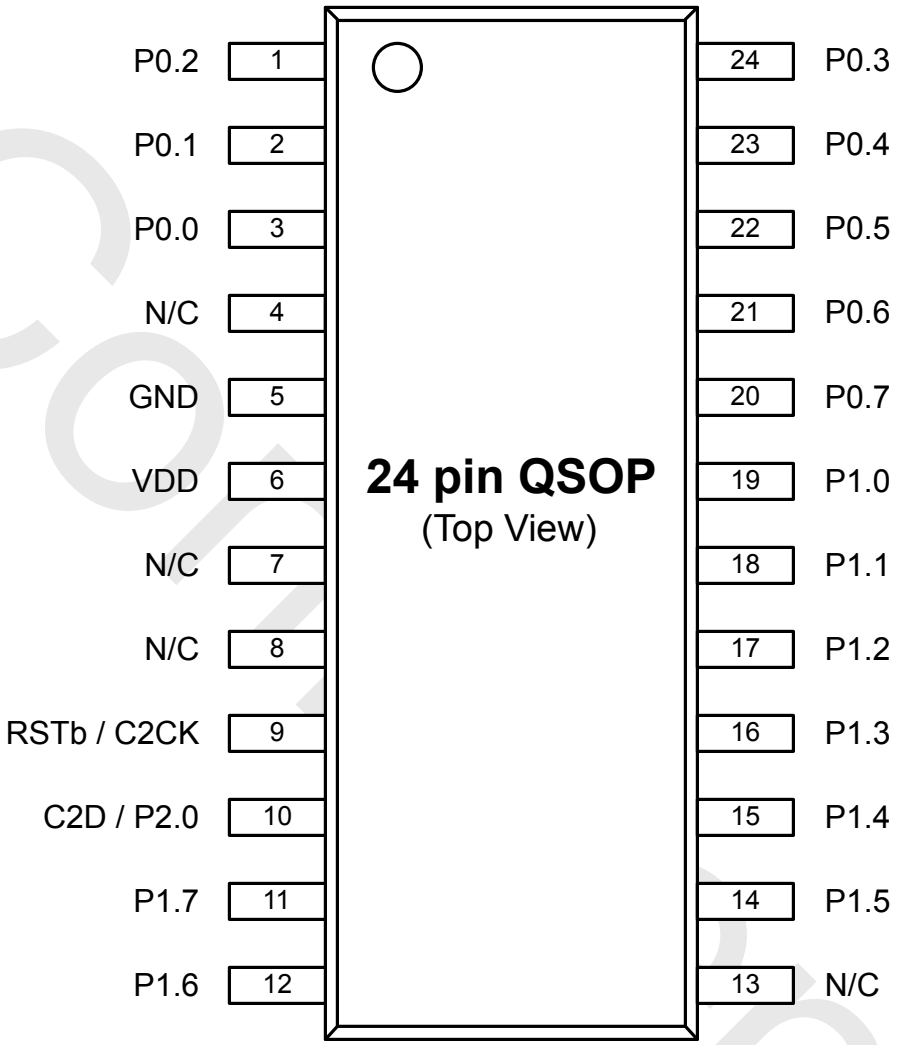

Figure 4.3. EFM8SB1x-QSOP24 Pinout

Table 4.3. Pin Definitions for EFM8SB1x-QSOP24

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.2	Multifunction I/O	Yes	P0MAT.2 RTCOUT INT0.2 INT1.2	ADC0.2 CS0.2 XTAL1
2	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CS0.1 AGND
3	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	CS0.0 VREF

Pin Numbers	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
4	N/C	No Connection			
5	GND	Ground			
6	VDD	Supply Power Input			
7	N/C	No Connection			
8	N/C	No Connection			
9	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
10	P2.7 / C2D	Multifunction I/O / C2 Debug Data			
11	P1.7	Multifunction I/O	Yes	P1MAT.7	XTAL4
12	P1.6	Multifunction I/O	Yes	P1MAT.6	XTAL3
13	N/C	No Connection			
14	P1.5	Multifunction I/O	Yes	P1MAT.5	CS0.13
15	P1.4	Multifunction I/O	Yes	P1MAT.4	CS0.12
16	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CS0.11
17	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CS0.10
18	P1.1	Multifunction I/O	Yes	P1MAT.1	CMP0N.4 CS0.9
19	P1.0	Multifunction I/O	Yes	P1MAT.0	CMP0P.4 CS0.8
20	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CS0.7 IREF0
21	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CS0.6
22	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CS0.5
23	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CS0.4
24	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK WAKEOUT INT0.3 INT1.3	ADC0.3 CS0.3 XTAL2

5. QFN20 Package Specifications

5.1 QFN20 Package Dimensions

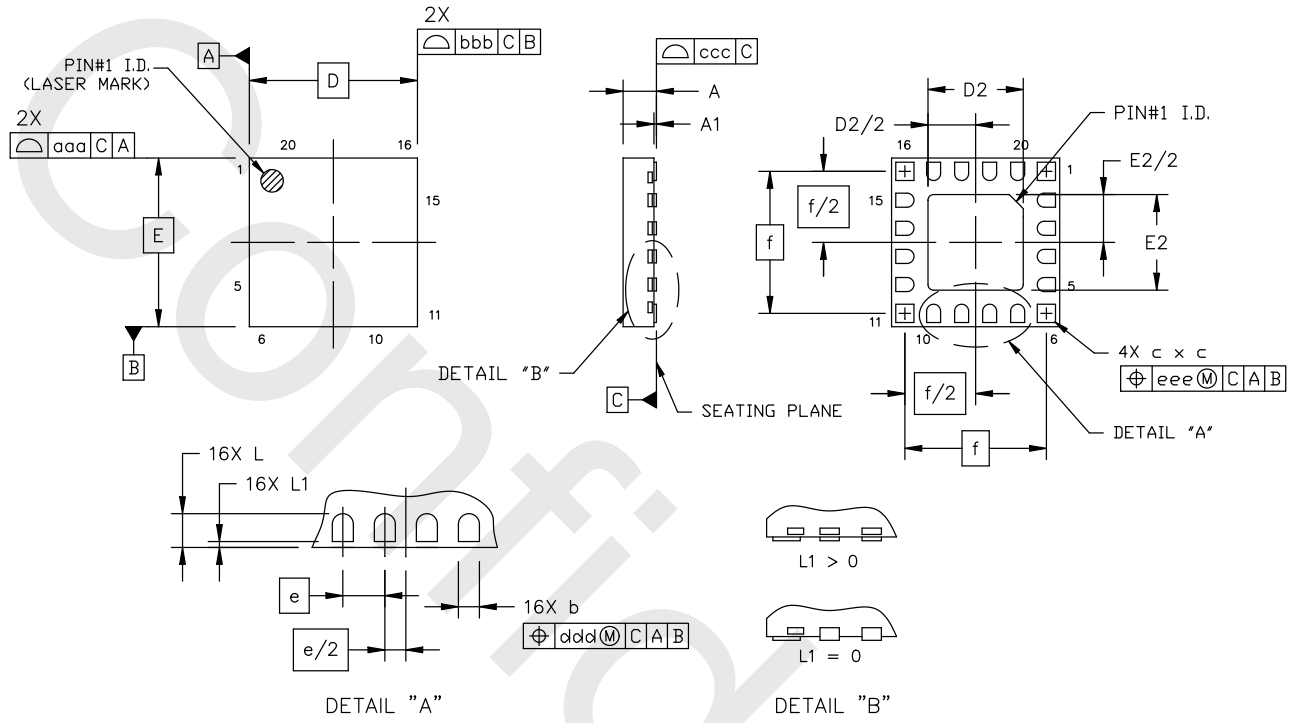

Figure 5.1. QFN20 Package Drawing

Table 5.1. QFN20 Package Dimensions

Dimension	Min	Typ	Max
A	0.50	0.55	0.60
A1	0.00	0.02	0.05
b	0.20	0.25	0.30
c	0.27	0.32	0.37
D		3.00 BSC	
D2	1.6	1.70	1.8
e		0.50 BSC	
E		3.00 BSC	
E2	1.6	1.70	1.8
f		2.53 BSC	
L	0.3	0.40	0.5
L1	0.00	—	0.10
aaa	—	—	0.05

Dimension	Min	Typ	Max
bbb	—	—	0.05
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10

Note:

1. All dimensions are shown in millimeters unless otherwise noted.
2. Dimensioning and tolerancing per ANSI Y14.5M-1994.

5.2 QFN20 PCB Land Pattern

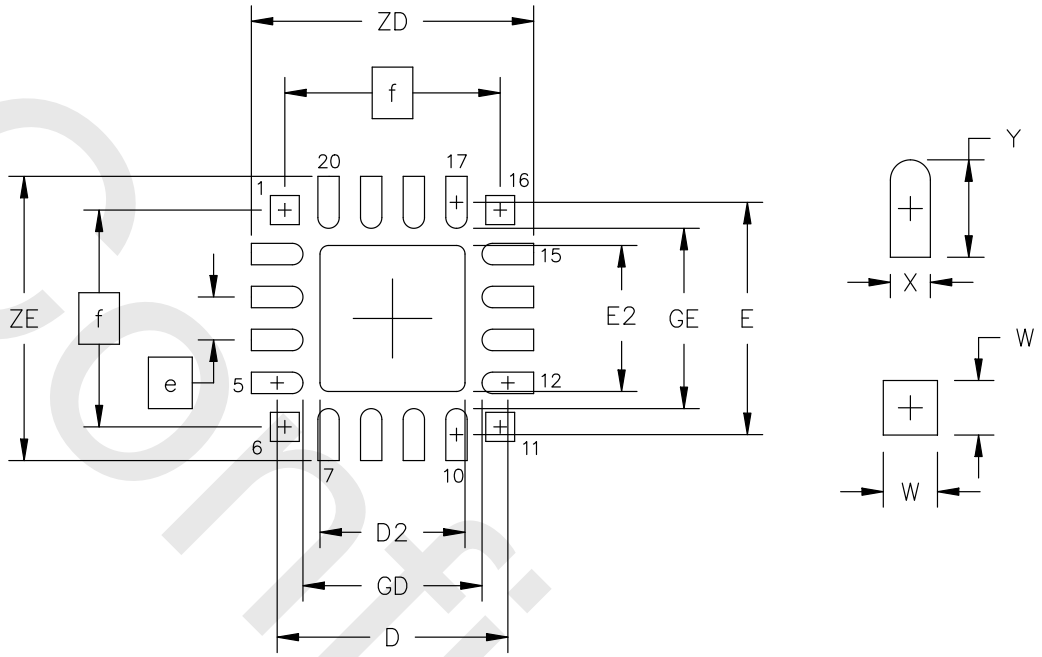

Figure 5.2. QFN20 PCB Land Pattern Drawing

Table 5.2. QFN20 PCB Land Pattern Dimensions

Dimension	Min	Max
D	2.71 REF	
D2	1.60	1.80
e	0.50 BSC	
E	2.71 REF	
E2	1.60	1.80
f	2.53 BSC	
GD	2.10	—
GE	2.10	—
W	—	0.34
X	—	0.28
Y	0.61 REF	
ZE	—	3.31
ZD	—	3.31

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on IPC-SM-782 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.
5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
7. The stencil thickness should be 0.125 mm (5 mils).
8. The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
9. A 1.45 x 1.45 mm square aperture should be used for the center pad. This provides approximately 70% solder paste coverage on the pad, which is optimum to assure correct component stand-off.
10. A No-Clean, Type-3 solder paste is recommended.
11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6. QFN24 Package Specifications

6.1 QFN24 Package Dimensions

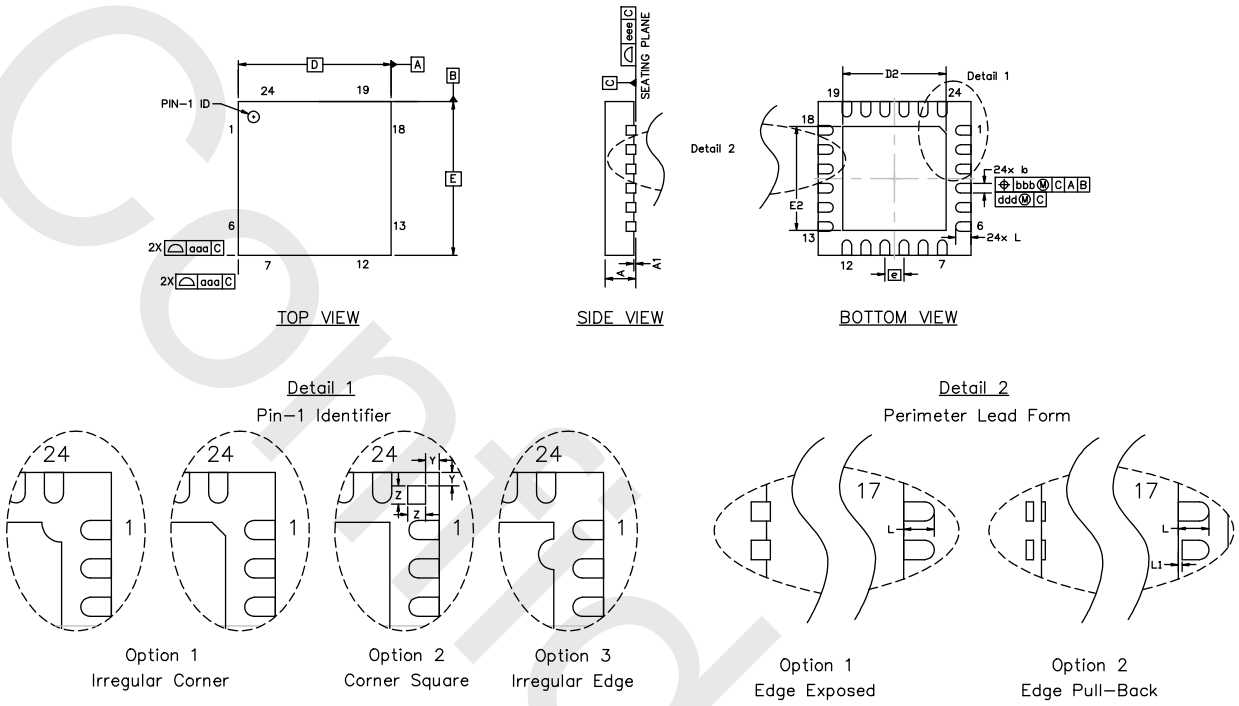

Figure 6.1. QFN24 Package Drawing

Table 6.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		4.00 BSC	
D2	2.55	2.70	2.80
e		0.50 BSC	
E		4.00 BSC	
E2	2.55	2.70	2.80
L	0.30	0.40	0.50
L1	0.00	—	0.15
aaa	—	—	0.15
bbb	—	—	0.10

Dimension	Min	Typ	Max
ddd	—	—	0.05
eee	—	—	0.08
Z	—	0.24	—
Y	—	0.18	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220, variation WGGD except for custom features D2, E2, Z, Y, and L which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

6.2 QFN24 PCB Land Pattern

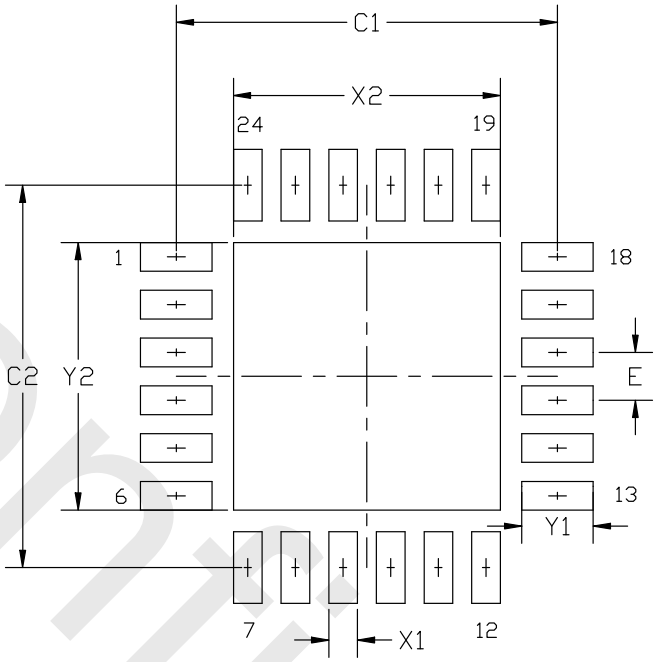

Figure 6.2. QFN24 PCB Land Pattern Drawing

Table 6.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.90	4.00
C2	3.90	4.00
E	0.50 BSC	
X1	0.20	0.30
X2	2.70	2.80
Y1	0.65	0.75
Y2	2.70	2.80

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A 2 x 2 array of 1.0 mm x 1.0 mm openings on a 1.30 mm pitch should be used for the center pad.
8. A No-Clean, Type-3 solder paste is recommended.
9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7. QSOP24 Package Specifications

7.1 QSOP24 Package Dimensions

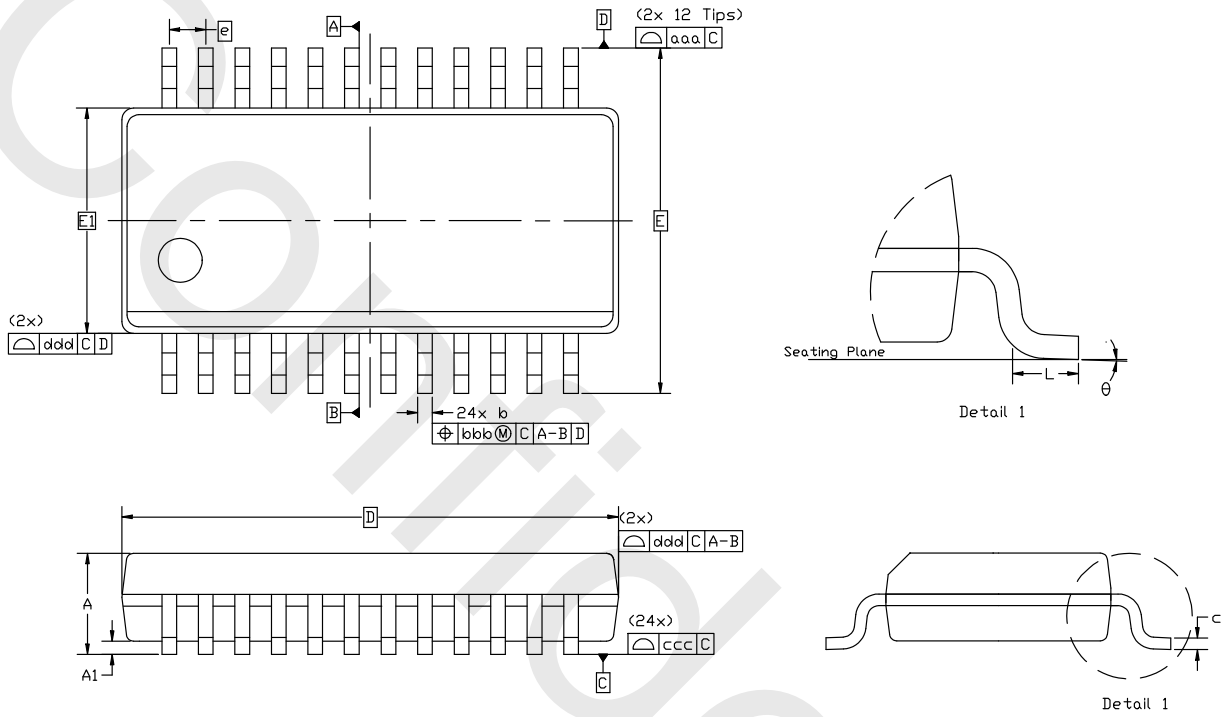

Figure 7.1. QSOP24 Package Drawing

Table 7.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°
aaa	0.20		

Dimension	Min	Typ	Max
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

7.2 QSOP24 PCB Land Pattern

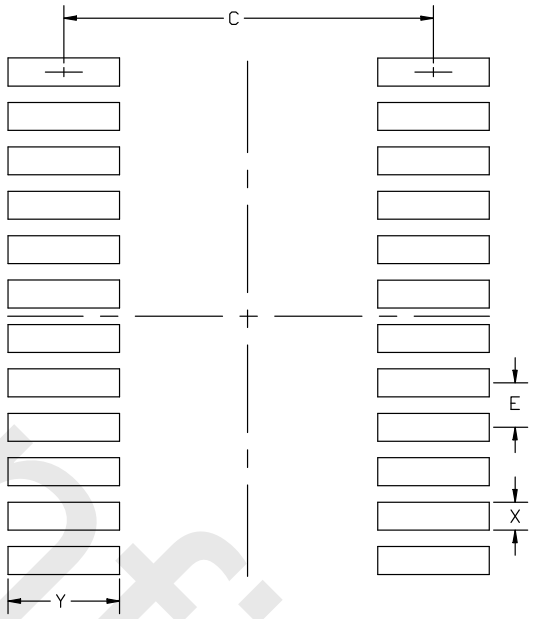

Figure 7.2. QSOP24 PCB Land Pattern Drawing

Table 7.2. QSOP24 PCB Land Pattern Dimensions

Dimension	Min	Max
C	5.20	5.30
E	0.635 BSC	
X	0.30	0.40
Y	1.50	1.60

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This land pattern design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A No-Clean, Type-3 solder paste is recommended.
8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

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